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CJC

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Gao et al.

Attorney Docket No.: KLA1P112/P1116

Patent: 7,359,544 B2

Issued: April 15, 2008

Title: Automatic Supervised Classifier Setup Tool
for Semiconductor Defects

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on August 1, 2008 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed: _____

Quyen N. Vuong

**REQUEST FOR CERTIFICATE OF CORRECTION
OF OFFICE MISTAKE
(35 U.S.C. §254, 37 CFR §1.322)**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450
Attn: Certificate of Correction

**Certificate
AUG 06 2008
of Correction**

Dear Sir:

Attached is Form PTO-1050 (Certificate of Correction) at least one copy of which is suitable for printing. The errors together with the exact page and line number where the errors are shown correctly in the application file are as follows:

CLAIMS:

1. In line 7 of claim 11 (column 13, line 7) change "max/min algorithm until" to --max/min algorithm until 1/4--. This appears correctly in the Amendment B as filed on September 18, 2007, on page 6, line 15.

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It is noted that the above-identified errors were printing errors that apparently occurred during the printing process. Accordingly, it is believed that no fees are due in connection with the filing of this Request for Certificate of Correction. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 504480 (Order No. KLA1P112/P1116/PRO).

Respectfully submitted,
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(Also Form PT-1050)

UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO. : 7,359,544 B2

DATED : April 15, 2008

Page 1 of 1

INVENTOR(S) : Gao et al.

It is certified that error appears in the above-identified patent and that said Letters Patent are hereby corrected as shown below:

CLAIMS:

1. In line 7 of claim 11 (column 13, line 7) change "max/min algorithm until" to --max/min algorithm until 1/4--.

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9. (currently amended) A method as recited in claim 1, wherein ~~determining the~~ selecting each first representative set of defects includes selecting defects which are uniformly distributed across a feature space to be included within the each first representative set.

10. (currently amended) A method as recited in claim 1, wherein ~~determining the~~ selecting each first representative set of defects includes selecting defects which are the most diverse to be included within the each first representative set.

11. (currently amended) A method as recited in claim 1, wherein the one or more first representative sets only includes a single first representative set and wherein ~~determining the~~ selecting each first representative set of defects comprises:

when the defects total is less than three, selecting all of the defects to be included within the single first representative set; and

when the defects total is are equal to three or more, selecting defects based on a ~~the~~ max/min algorithm until $\frac{1}{4}$ of the defects are selected to be included within the single first representative set.

12. (currently amended) A method as recited in claim 3, wherein ~~determining the~~ selecting each first representative set of defects for each group comprises:

when the defects for the each group total less than three, selecting all of the defects from the each group to be included within the each first representative set for such group; and

when the defects for the each group are equal to three or more, selecting defects from the each group based on a ~~the~~ max/min algorithm until $\frac{1}{4}$ of the defects are selected to be included within the each first representative set for such each group.

13. (currently amended) A method as recited in claim 3, further comprising:

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